

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10593736	MIYATAKE ET AL.
Examiner	Art Unit	
DEREK S CHAPEL	2872	

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
Consulted with Arnel Lavarias about the restriction	1/16/2009	DSC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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